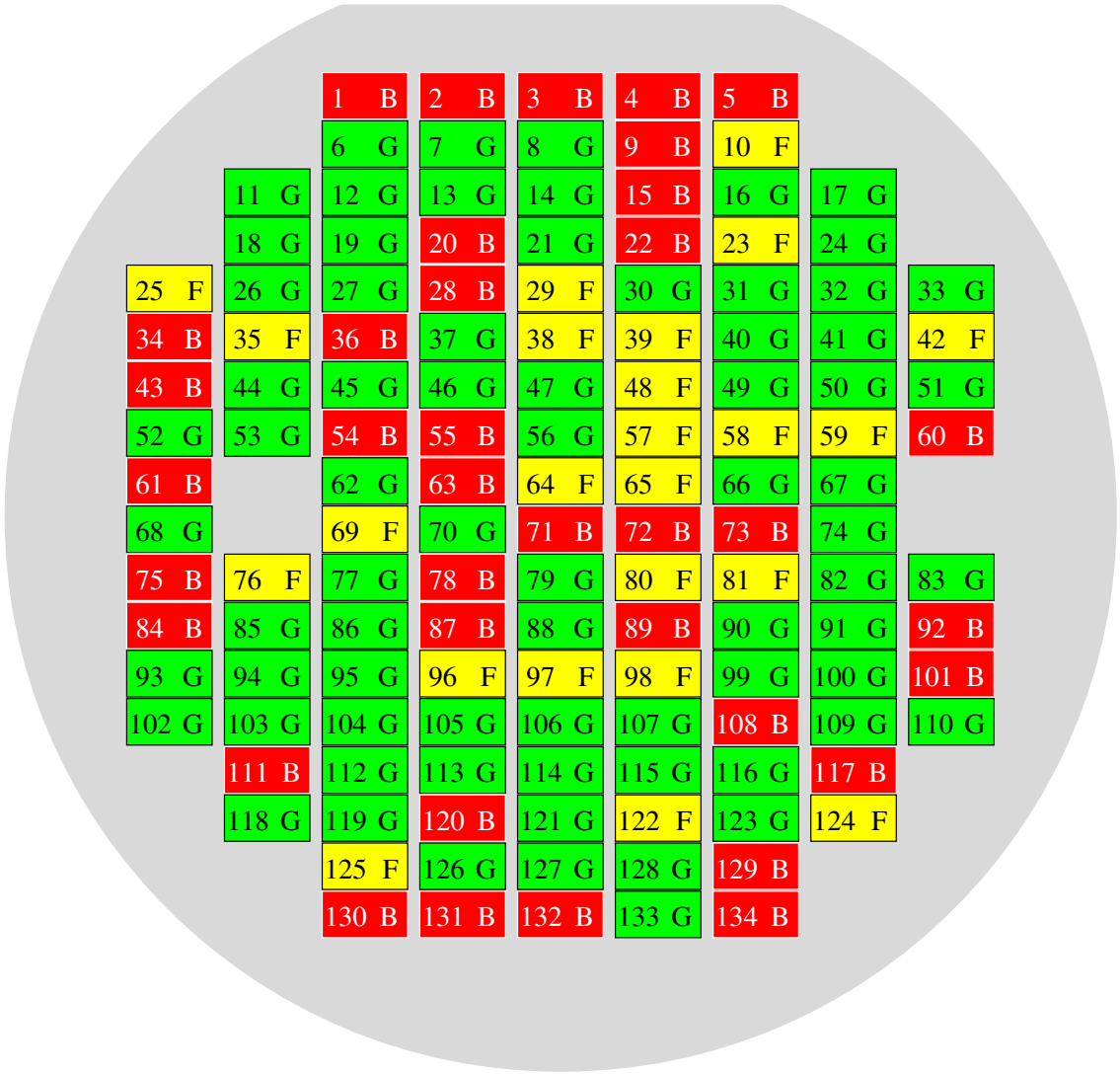
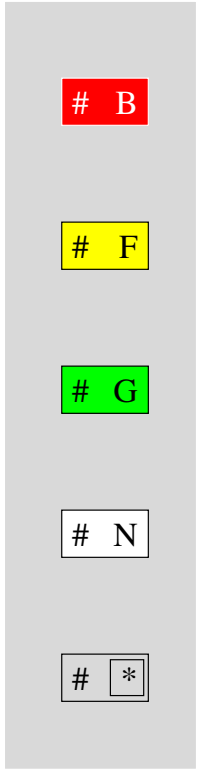
Die quality map for wafer 180 s/n: Y21316-09-17

Date: 07/09/99





Bad die

Fair die

Good die

No info

Manually tagged